

Electronic Supplementary Information: Chip-on-Foil Devices for DNA Analysis Based on Inkjet-Printed Silver Electrodes

Sebastian Wünscher,^{a,b,‡} Barbara Seise,^{d,e,‡} David Pretzel,^{a,b} Sibyll Pollok,^{d,e} Jolke Perelaer,^{a,b,c} Karina Weber,^{d,e} Jürgen Popp,^{d,e} Ulrich S. Schubert^{a,b,c,*}

^a Laboratory of Organic and Macromolecular Chemistry (IOMC), Friedrich Schiller University Jena, Humboldtstr. 10, 07743 Jena, Germany.

^b Jena Center for Soft Matter (JCSM), Friedrich Schiller University Jena, Philosophenweg 7, 07743 Jena, Germany.

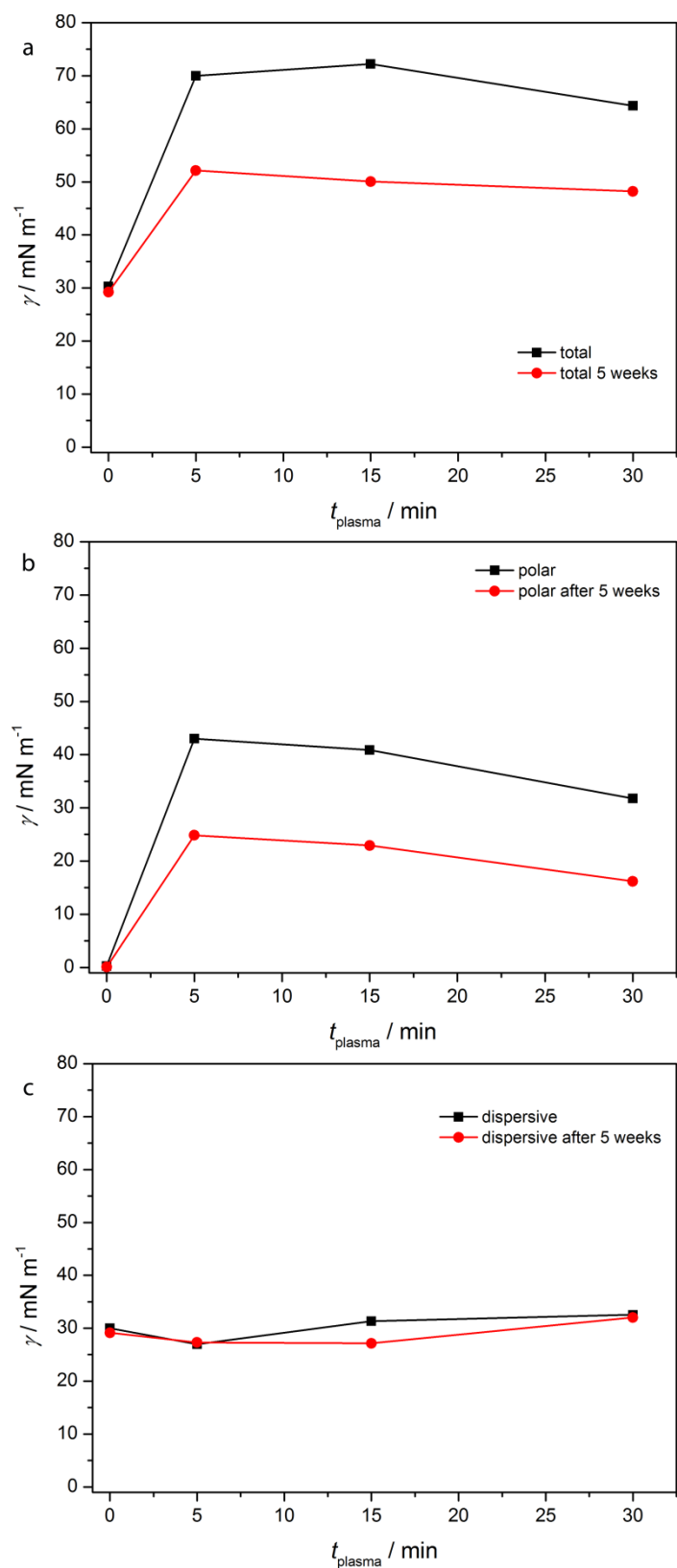
^c Dutch Polymer Institute (DPI), PO Box 513, 5600 MB Eindhoven, The Netherlands.

^d Institute of Photonic Technology, Albert-Einstein-Str. 9, 07745 Jena, Germany.

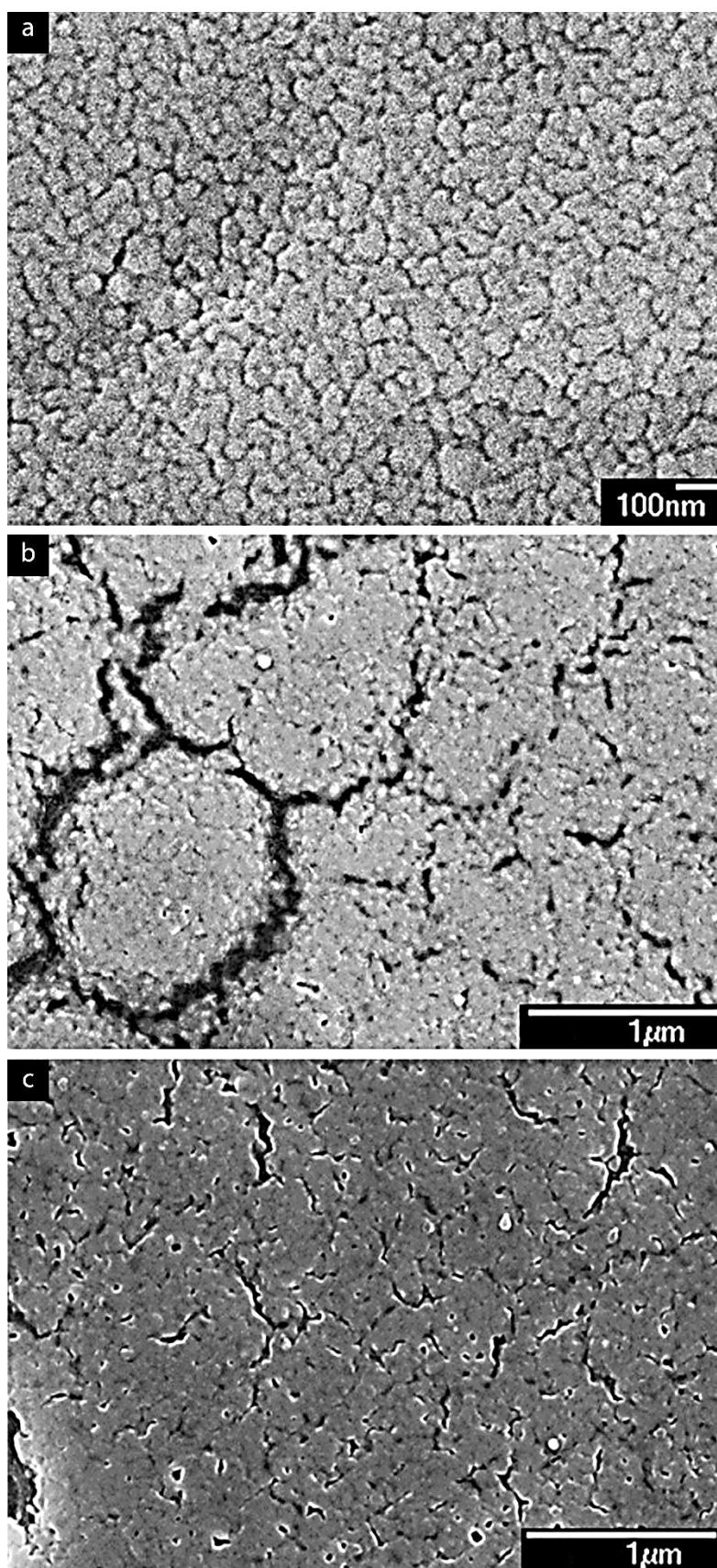
^e Institute of Physical Chemistry and Abbe Center of Photonics, Friedrich Schiller University Jena, Helmholtzweg 4, 07743 Jena, Germany.

‡ Both authors contributed equally to the presented work.

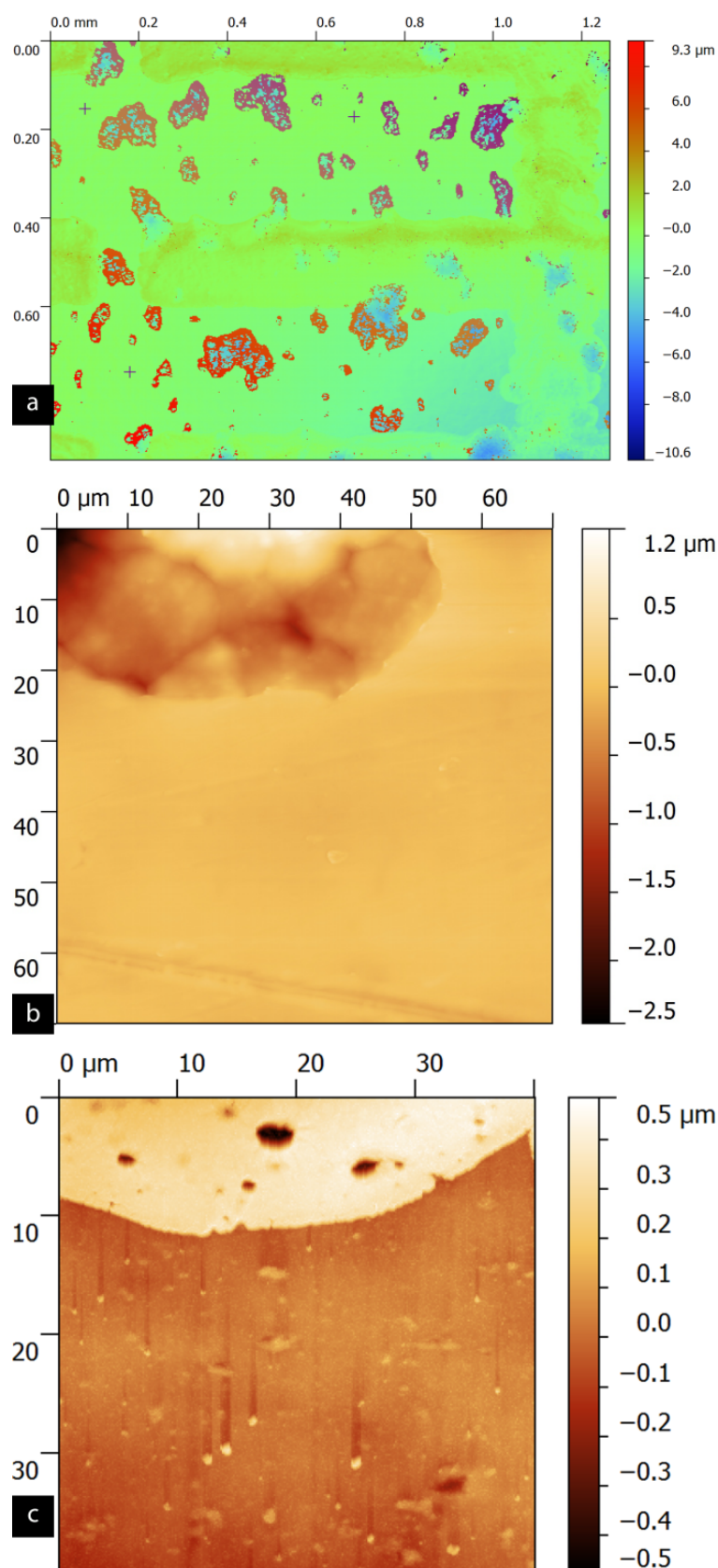
Email: ulrich.schubert@uni-jena.de



Supplementary Information Figure 1. Total surface energy γ (a); polar (b) and dispersive (c) fraction of the total surface energy of polypropylene foil in dependence of plasma treatment time.

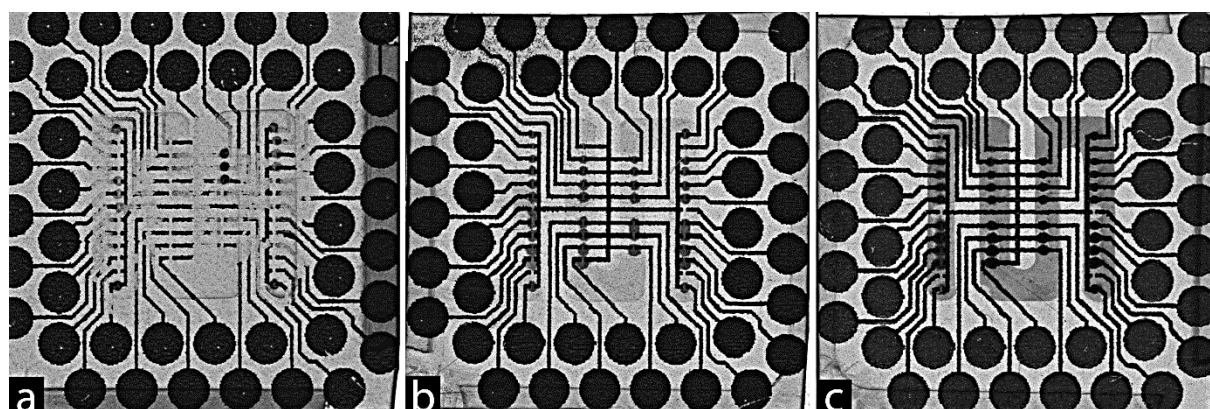


Supplementary Information Figure 2. SEM images of as-printed (a), 15 min argon plasma sintered (b) and 30 min argon plasma sintered (c) Harima NPS-J electrodes.



Supplementary Information Figure 3. 2D profile of Harima NPS-J electrodes on PP foil (a); atomic force microscopy image (AFM) of PP foil (b) and low pressure argon plasma sintered (30 min) Harima NPS-J electrode (c).

Supplementary Information Figure 4a shows multiple defects of a size of up to $200\text{ }\mu\text{m} \times 200\text{ }\mu\text{m}$ on the surface of the PP foil. The depth of these defects ranges between $0.2\text{ }\mu\text{m}$ to more than $1\text{ }\mu\text{m}$, which exceeding the height of a single layer printed silver track. Height measurements are therefore not reliable. Additionally, different analysis methods, like optical profilometry and AFM, of the same structure result in different height values of $0.53\text{ }\mu\text{m}$ and $0.34\text{ }\mu\text{m}$, respectively.



Supplementary information Figure 4. Adhesion and background signal for analysis chips printed from Harima NPS-J after low pressure argon plasma sintering for 5 minutes (**a**), 15 minutes (**b**) and 30 minutes (**c**).